

Notice of References Cited		Application/Control No. 09/886,081	Applicant(s)/Patent Under Reexamination GORIN ET AL.	
		Examiner Thomas H. Stevens	Art Unit 2123	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,740,007	04-1998	Nakaie et al.	361/220
	B	US-6,512,362	01-2003	Gieser, Horst	324/158.1
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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X	N	07098355	04-1995			
X	O	61256266	11-1986			
X	P	0789249	08-1997			
	Q					
	R					
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	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
X	U	JEDEC Standard JESD22-C101 EIA May 1995 pg. 1-4
X	V	Suzuki-K et al., "A New CDM Test Method and Protective Circuits against the Excessive Mobile Charge" 1998 pg. 1065-1069.
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.